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Electrically Based Microstructural Characterization II

Editors: Rosario A. Gerhardt, Mohammad A. Alim and S. Ray Taylor

Table of Contents

[More information](#)

CONTENTS

Preface	xi
Materials Research Society Symposium Proceedings	xii

**PART I: ADVANCES IN LOCALIZED
ELECTRICAL TESTING**

*Low-Frequency Scanning Capacitance Microscopy	3
<i>S. Lányi and M. Hruskovic</i>	
Resistometric Mapping Using a Scanning Tunneling Microscope	15
<i>C.I. Lang and J. Tapson</i>	
Micromachined SFM Probes for High-Frequency Electric and Magnetic Fields	21
<i>D.W. van der Weide, V. Agrawal, P. Neuzil, and T. Bork</i>	
Measurement of Stratified Distributions of Dielectric Properties and Dependent Physical Parameters	29
<i>A.V. Mamishev, Y. Du, B.C. Lesieutre, and M. Zahn</i>	
Understanding Coating and Substrate Heterogeneities Using Electrochemical Impedance Methods	35
<i>A.M. Mierisch and S.R. Taylor</i>	
Electromechanical Study of Carbon Fiber Composites	43
<i>Xiaojun Wang, Xuli Fu, and D.D.L. Chung</i>	
Formation of Dislocations in NiAl Single Crystals Studied by <i>In Situ</i> Electrical Resistivity Measurement	49
<i>Y.Q. Sun, P.M. Hazzledine, and D.M. Dimiduk</i>	

**PART II: SEMICONDUCTOR AND
MICROELECTRONIC APPLICATIONS**

A Novel Approach to Semiconductor Electrical Properties— The Advanced Method of Transient Microwave Photoconductivity (AMTMP)	57
<i>S. Grabtchak and M. Cocivera</i>	
Microstructural and Electrical Characterization of Misfit Dislocations at the InAs/GaP Heterointerface	63
<i>V. Gopal, T.P. Chin, A.L. Vasiliev, J.M. Woodall, and E.P. Kvam</i>	

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Table of Contents

[More information](#)

Electrical Measurement of the Bandgap of N⁺ and P⁺ SiGe Formed by Ge Ion Implantation	69
<i>Akira Nishiyama, Osamu Arisumi, and Makoto Yoshimi</i>	
Investigation of the Dopant Distribution in Thin Epitaxial Silicon Layers by Means of Spreading Resistance Probe and Secondary Ion Mass Spectrometry	75
<i>Ilya Karpov, Catherine Hartford, Greg Moran, Subramania Krishnakumar, Ron Chorna, and Jack Linn</i>	
Evaluation of Gap States in Hydrogen-Terminated Silicon Surfaces and Ultrathin SiO₂/Si Interfaces by Using Photoelectron Yield Spectroscopy	81
<i>S. Miyazaki, T. Tamura, T. Maruyama, H. Murakami, A. Kohno, and M. Hirose</i>	
Conductance Transients Study of Slow Traps in Al/SiN_x:H/Si and Al/SiN_x:H/InP Metal-Insulator-Semiconductor Structures	87
<i>S. Dueñas, R. Peláez, E. Castán, J. Barbolla, I. Mártel, and G. Gonzalez-Diaz</i>	
The Influence of Ionic Activity on the Electrical Properties of PECVD (TEOS) Silicon Dioxide	93
<i>A. Romanelli Cardoso, M.L. Pereira da Silva, and J.J. Santiago-Aviles</i>	
Analysis of TEOS Silicon Dioxide: The Identification of Carbonaceous Contaminants	97
<i>M.L. Pereira da Silva, A. Romanelli Cardoso, and J.J. Santiago-Aviles</i>	
Electrical Properties of Integrated Ta₂O₅ Metal-Insulator-Metal Capacitors	101
<i>B.C. Martin, C. Basceri, S.K. Streiffer, and A.I. Kingon</i>	
Effects of Sc or Tb Addition on the Microstructures and Resistivities of Al Thin Films	107
<i>Shinji Takayama</i>	
Electrical Properties of Novel Anodic Films Formed in Nonaqueous Electrolyte Solutions	113
<i>F. Mizutani, S. Takeuchi, T. Nishiwaki, N. Sato, and M. Ue</i>	
Anodic Oxidation of Nitrogen-Added Al-Based Alloys for Thin-Film Transistors	119
<i>Toshiaki Arai and Hideo Iiyori</i>	
Nucleation and Growth at Reactive Interfaces Followed by Impedance Measurements	125
<i>F. Voiron, M. Ignat, T. Marieb, and H. Fujimoto</i>	
PART III: <u>MAGNETIC AND POLYMERIC MATERIALS</u>	
Giant Magnetoimpedance: A Relevant Application of Impedance Spectroscopy	133
<i>K.L. García and R. Valenzuela</i>	

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Electrically Based Microstructural Characterization II

Editors: Rosario A. Gerhardt, Mohammad A. Alim and S. Ray Taylor

Table of Contents

[More information](#)

Electromagnetic Properties of Soils 137
J.C. Santamarina and K.A. Klein

**Magnetic Transitions Studied by Electrically-Based Methods
 in Mn-Zn Ferrite** 147
P. Gutiérrez, A. Peláiz, A. Huanosta, and R. Valenzuela

**Application of Broad-Band Dielectric Spectroscopy for
 Investigations of Liquid Crystal-Porous Media Microcomposites** 151
G.P. Sinha, B. Batalla, and F.M. Aliev

**Study of the Molecular Mobility of Polysaccharide Solid
 Thin Layers by Dielectric Relaxation Spectroscopy** 157
K. Liedermann, L. Lapcik, Jr., and S. Desmedt

PART IV: DIELECTRICS AND FERROELECTRICS

***Universality of Dielectric Response as an Aid to Diagnostics** 167
Andrew K. Jonscher

The Dielectric Loss of Single Crystal and Polycrystalline TiO₂ 183
Xiaoru Wang, Alan Templeton, Stuart J. Penn, and Neil Mcn. Alford

Very Low Loss Ceramic Dielectric Resonator Materials 189
*N. Mcn. Alford, S.J. Penn, A. Templeton, X. Wang, P. Filhol,
 N. Klein, C. Zuccaro, and J.C. Gallop*

**Complex Dielectric Spectroscopy Characterization of a
 Li_{0.982}Ta_{1.004}O₃ Ferroelectric Single Crystal** 195
Ming Dong and Rosario A. Gerhardt

PART V: VARISTORS

***Time Domain Response of Electrical Ceramics Micro
 to Megaseconds** 203
F.A. Modine

***Quantitative ICTS Measurement of Interface States
 at Grain Boundaries in ZnO Varistors** 213
K. Mukae and A. Tanaka

***Current Localization, Non-Uniform Heating, and Failures
 of ZnO Varistors** 221
M. Bartkowiak

***Current Flow and Structural Inhomogeneities in Nonlinear
 Materials** 235
F. Greuter, T. Christen, and J. Glatz-Reichenbach

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Cambridge University Press

978-1-107-41355-9 - Materials Research Society Symposium Proceedings: Volume 500:
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Editors: Rosario A. Gerhardt, Mohammad A. Alim and S. Ray Taylor

Table of Contents

[More information](#)

**High-Power Switching Behavior in Conductor-Filled
Polymer Composites** 247
Anil R. Duggal and Lionel M. Levinson

Computer Simulation of ZnO Varistors Failures 253
M. Bartkowiak, G.D. Mahan, M.G. Comber, and M.A. Alim

PART VI: IONIC AND MIXED CONDUCTORS

***Non-Debye and CPA Behaviors of Ionic Materials** 261
J.C. Wang

**Impedance Spectroscopy of Nanocrystalline Y-Stabilized
Tetragonal Zirconia** 273
P. Mondal and H. Hahn

**Microstructural Correlation with Electrical Properties for
Y₂O₃-Doped CeO₂ Thin Films** 279
Chunyan Tian and Siu-Wai Chan

**Correlation Between Electrical Properties and Composition/
Microstructure of Si-C-N Ceramics** 285
C. Haluschka, C. Engel, R. Riedel, H-J. Kleebe, and R. Franke

***The Use of Computer Simulations to Interpret and Understand
Electrical Measurements** 291
Edward J. Garboczi

**Characterizing the Dispersion of Constituents in Concrete
by Electrical Resistivity** 303
Pu-Woei Chen, Xuli Fu, and D.D.L. Chung

**Electrochemical Corrosion of Electrodes in a Simulated
Nuclear Waste Glass Melt** 309
S.K. Sundaram

**Extended D.C. Electrical Transport Measurements on the
Mixed Conductor Cu₃CS₂** 315
P.K. Lemaire, J. Benoit, and R. Speel

Stability and Conductivity of Gd₂((Mo_{1/3}Mn_{2/3})_xTi_{1-x})₂O₇ 321
J.J. Sprague, O. Porat, and H.L. Tuller

**Composition-Dependent Electrical Conductivity of
Ionic-Electronic Composite** 327
Y.M. Park and G.M. Choi

*Invited Paper

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Editors: Rosario A. Gerhardt, Mohammad A. Alim and S. Ray Taylor

Table of Contents

[More information](#)**PART VII: COMPOSITES AND PERCOLATION SYSTEMS**

Comparison of Techniques for Microwave Characterization of Percolating Dielectric—Metallic Media and Resolution of Discrepancies in Measured Data	335
<i>Rick Moore, Lisa Lust, Edward Hopkins, and Paul Friederich</i>	
Dielectric Spectroscopy of Insulator/Conductor Composites	341
<i>Julie Runyan Kokan, Rosario Gerhardt, Robert Ruh, and David S. McLachlan</i>	
Computer Simulation of Impedance for 2-D Conductor-Insulator Composite	347
<i>Dae Gon Han and Gyeong Man Choi</i>	
Scaling Behavior of the Complex Conductivity of Graphite-Boron Nitride Percolation Systems	351
<i>Jungie Wu and D.S. McLachlan</i>	
Conductivity and Noise Measurements in 3-D Percolative Cellular Structures	357
<i>C. Chiteme and D.S. McLachlan</i>	
Author Index	363
Subject Index	365